Docket No.: 061282-0055 PATENT

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

re Application of : Customer Number: 20277

Takeshi KOBAYASHI, et al. : Confirmation Number: 4950

Application No.: 10/757,388 : Group Art Unit: 2814

Filed: January 15, 2004 : Examiner: Dilinh P. Nguyen

For: LEAD FRAME, METHOD OF MANUFACTURING THE SAME, SEMICONDUCTOR

DEVICE USING LEAD FRAME AND METHOD OF MANUFACTURING

SEMICONDUCTOR DEVICE

## INFORMATION DISCLOSURE STATEMENT

Mail Stop RCE Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Dear Sir:

NOV 0 6 2006

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached form PTO-1449. It is respectfully requested that the references be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This Information Disclosure Statement is being filed within three months of the U.S. filing date OR before the mailing date of a first Office Action on the merits. No certification or fee is required.

Each non-English language reference was first cited in a corresponding foreign application search report or office action and its relevance discussed therein. A copy of the

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foreign search report or office action, together with an English language version thereof, is attached for the Examiner's information.

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

Respectfully submitted,

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Facsimile: 202.756.8087 **Date: November 6, 2006** 

Please recognize our Customer No. 20277 as our correspondence address.

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					APPLICANT Takeshi KOBA	APPLICANT Takeshi KOBAYASHI, et al.					
(PTO-1449)					FILING DATE  January 15, 200	GROUP <b>2814</b>					
			U	S. PATEN	T DOCUMENTS						
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code2 (if known)		Publication Dat MM-DD-YYYY		Name of Patentee or Applicant of Cited Document			Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
	ļ	US 6,339,261 B1		01/15/2002	Yonemochi et a	Yonemochi et al.					
		US 2002/0027265 A1		03/07/2002	Yoneda et al.						
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INITIALS	CITE NO.	Foreign Patent Document Country Codes -Number 4 -Kind Codes (if known)		MM-DD-YYYY	Applicant of Cited Document	Whe	Where Relevant		No		
	1	1	EP 0 977 259 A2	02/02/2000	Fujitsu Limited			X			
		EP 0 999 587 A2		05/10/2000	Shinko Electric Industries Co. Ltd.			х			
		EP 0 645 952 A1		03/29/1995	Rogers Corporation			X			
		JP 11 067838		03/09/1999	Matsushita Electric Industrial Co., Ltd.			English Abstract			
	5		JP 56 148846	11/18/1981	NEC Corporation			Japan w/ English Abstract			
		JP 06 148661		05/27/1994	Matsushita Electric Industrial Co., Ltd.	Co., Ltd.		Japan w/ English Abstract			
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EXAMINER						DATE CONSIDERED					

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.